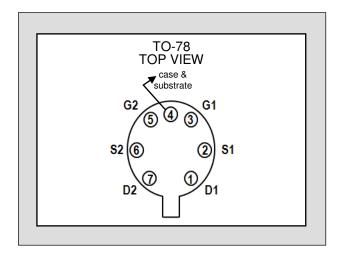


Linear Integrated Systems

FEATURES						
DIRECT REPLACEMENT FOR INTERSIL 3N190 & 3N191						
LOW GATE LEAKAGE CURRENT	$I_{GSS} \le \pm 10pA$					
LOW TRANSFER CAPACITANCE	$C_{rss} \le 1.0pF$					
ABSOLUTE MAXIMUM RATINGS ¹						
@ 25 ℃ (unless otherwise stated)						
Maximum Temperatures						
Storage Temperature	-65 to +150 ℃					
Operating Junction Temperature -55 to +135 ℃						
Maximum Power Dissipation @ TA=25°C						
Continuous Power Dissipation One Side	300mW					
Continuous Power Dissipation Both Sides	525mW					
Maximum Current						
Drain to Source ²	50mA					
Maximum Voltages						
Drain to Gate ²	30V					
Drain to Source ²	30V					
Gate to Gate	±80V					

3N190 3N191

P-CHANNEL DUAL MOSFET ENHANCEMENT MODE



MATCHING CHARACTERISTICS @ 25 °C (unless otherwise stated) (V_{BS} = 0V unless otherwise stated)

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
gfs1/gfs2	Forward Transconductance Ratio	0.85		1.0		$V_{DS} = -15V$, $I_D = -500\mu A$, $f = 1kHz$
V _{GS1-2}	Gate to Source Threshold Voltage Differential			100	mV	$V_{DS} = -15V$, $I_D = -500\mu A$
$\frac{\Delta V_{\text{GS1 - 2}}}{\Delta T}$	Gate to Source Threshold Voltage Differential with Temperature ⁴			100	µV/°C	$V_{DS} = -15V$, $I_{D} = -500\mu A$ $T_{S} = -55$ to $+25$ °C
$\frac{\Delta V_{GS1-2}}{\Delta T}$	Gate to Source Threshold Voltage Differential with Temperature ⁴			100	μν/ Ο	$V_{DS} = -15V$, $I_D = -500\mu A$ $T_S = +25$ to $+125$ °C

ELECTRICAL CHARACTERISTICS @ 25 °C (unless otherwise stated) (V_{SB} = 0V unless otherwise stated)

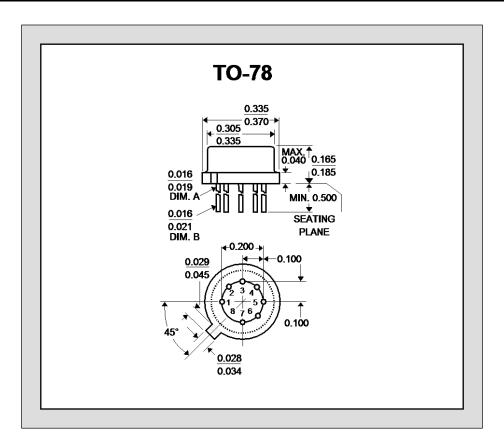
SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
BV _{DSS}	Drain to Source Breakdown Voltage	-40				$I_D = -10\mu A$
BV _{SDS}	Source to Drain Breakdown Voltage	-40			V	$I_S=-10\mu A,\ V_{BD}=0V$
V_{GS}	Gate to Source Voltage	-3.0		-6.5		$V_{DS} = -15V, I_D = -500 \mu A$
$V_{GS(th)}$	Gate to Source Threshold Voltage	-2.0		-5.0		$V_{DS} = V_{GS}$, $I_D = -10 \mu A$
V GS(th)	Gate to Source Threshold Voltage	-2.0		-5.0		$V_{DS} = -15V, I_D = -500 \mu A$
I _{GSSR}	Reverse Gate Leakage Current			10		$V_{GS} = 40V$
I _{GSSF}	Forward Gate Leakage Current			-10	pА	$V_{GS} = -40V$
I_{DSS}	Drain Leakage Current "Off"			-200		$V_{DS} = -15V$
I _{SDS}	Source to Drain Leakage Current "Off"			-400		$V_{SD} = -15V$, $V_{DB} = 0V$
I _{D(on)}	Drain Current "On" ³	-5.0		-30.0	mA	$V_{DS} = -15V, V_{GS} = -10V$
I _{G1G2}	Gate to Gate Isolation Current	-		±1.0	μΑ	$V_{G1G2} = \pm 80V, I_D = I_S = 0 = mA$

ELECTRICAL CHARACTERISTICS CONT. @ 25 °C (unless otherwise stated) (V_{SB} = 0V unless otherwise stated)

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
g fs	Forward Transconductance ⁴	1500		4000		$V_{DS} = -15V$, $I_{D} = -5mA$, $f = 1kHz$
gos	Output Admittance			300	μS	VDS = -13V, ID = -3IIIA, I = IKHZ
r _{ds(on)}	Drain to Source "On" Resistance			300	Ω	$V_{DS} = -20V, I_D = -100\mu A$
C_{rss}	Reverse Transfer Capacitance			1.0		
C _{iss}	Input Capacitance Output Shorted			4.5	рF	$V_{DS} = -15V$, $I_{D} = -5mA$, $f = 1MHz$
C _{oss}	Output Capacitance Input Shorted			3.0		

SWITCHING CHARACTERISTICS

SYMBOL	CHARACTERISTIC	MIN	TYP	MAX	UNITS	CONDITIONS
t _{d(on)}	Turn On Delay Time			15		
t _r	Turn On Rise Time			30	ns	$V_{DD} = -15V$, $I_{D(on)} = -5mA$, $R_G = R_L = 1.4k\Omega$
t _{off}	Turn Off Time			50		11G = 11E = 1.4K22



- 1. Absolute maximum ratings are limiting values above which serviceability may be impaired.
- 2. Per transistor.
- 3. Pulse: t = 300µs, Duty Cycle ≤ 3%
- 4. Measured at end points, T_A and T_B.

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